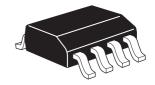


# ZXMN6A09DN8 60V SO8 N-channel enhancement mode MOSFET

# **Summary**

V <sub>(BR)DSS</sub>	$R_{DS(on)}\left(\Omega\right)$	I <sub>D</sub> (A)
60	0.040 @ V <sub>GS</sub> = 10V	5.6
	0.060 @ V <sub>GS</sub> = 4.5V	4.6



# **Description**

This new generation of trench MOSFETs from Zetex utilizes a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage power management applications.

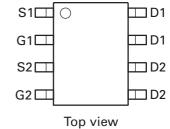
### **Features**

- · Low on-resistance
- · Fast switching speed
- · Low threshold
- · Low gate drive
- · SOIC package

# G1 G2 D2 S2 S2

# **Applications**

- DC-DC converters
- · Power management functions
- Disconnect switches
- · Motor control



# **Ordering information**

Device	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN6A09DN8TA	7	12	500

# **Device marking**

ZXMN 6A09D

# **Absolute maximum ratings**

Parameter	Symbol	Limit	Unit
Drain-source voltage	V <sub>DSS</sub>	60	V
Gate-source voltage	V <sub>GS</sub>	±20	V
Continuous drain current @ V <sub>GS</sub> =10V; T <sub>amb</sub> =25°C <sup>(b)</sup>	I <sub>D</sub>	5.6	Α
@ V <sub>GS</sub> =10V; T <sub>amb</sub> =70°C <sup>(b)</sup>		4.5	
@ V <sub>GS</sub> =10V; T <sub>amb</sub> =25°C <sup>(a)</sup>		4.3	
Pulsed drain current <sup>(c)</sup>	I <sub>DM</sub>	27	Α
Continuous source current (body diode)(b)	I <sub>S</sub>	3.5	Α
Pulsed source current (body diode)(c)	I <sub>SM</sub>	27	А
Power dissipation at $T_{amb} = 25^{\circ}C^{(a)(d)}$	$P_{D}$	1.25	W
Linear derating factor		10	mW/°C
Power dissipation at $T_{amb} = 25^{\circ}C^{(b)(e)}$	$P_{D}$	1.8	W
Linear derating factor		14	mW/°C
Power dissipation at $T_{amb} = 25^{\circ}C^{(b)(d)}$	P <sub>D</sub>	2.1	W
Linear derating factor		17	mW/°C
Operating and storage temperature range	T <sub>j</sub> , T <sub>stg</sub>	-55 to +150	°C

# Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient <sup>(a)(d)</sup>	$R_{\Theta JA}$	100	°C/W
Junction to ambient <sup>(a)(e)</sup>	$R_{\Theta JA}$	70	°C/W
Junction to ambient <sup>(b)(d)</sup>	$R_{\Theta JA}$	60	°C/W

### NOTES:

<sup>(</sup>a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

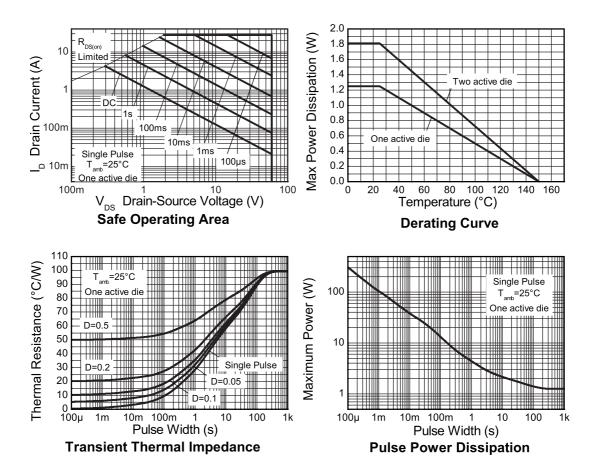
<sup>(</sup>b) For a device surface mounted on FR4 PCB measured at t  $\leq$ 10 sec.

<sup>(</sup>c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width  $300\mu s$  - pulse width limited by maximum junction temperature.

<sup>(</sup>d) For a dual device with one active die.

<sup>(</sup>e) For a device with two active die running at equal power.

## **Characteristics**



# Electrical characteristics (at T<sub>amb</sub> = 25°C unless otherwise stated)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions	
Static		'					
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	60			V	I <sub>D</sub> = 250μA, V <sub>GS</sub> =0V	
Zero gate voltage drain current	I <sub>DSS</sub>			1	μΑ	V <sub>DS</sub> = 60V, V <sub>GS</sub> =0V	
Gate-body leakage	I <sub>GSS</sub>			100	nA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	
Gate-source threshold voltage	V <sub>GS(th)</sub>	1.0		3.0	V	$I_D=250\mu A, V_{DS}=V_{GS}$	
Static drain-source on-state	R <sub>DS(on)</sub>			0.040	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 8.2A	
resistance <sup>(*)</sup>				0.060	Ω	$V_{GS} = 4.5V, I_D = 7.4A$	
Forward transconductance(*)(‡)	9 <sub>fs</sub>		15		S	V <sub>DS</sub> = 15V, I <sub>D</sub> = 8.2A	
Dynamic <sup>(‡)</sup>		'					
Input capacitance	C <sub>iss</sub>		1407		pF	V <sub>DS</sub> = 40V, V <sub>GS</sub> =0V	
Output capacitance	C <sub>oss</sub>		121		pF	f=1MHz	
Reverse transfer capacitance	C <sub>rss</sub>		59		pF		
Switching (†) (‡)		ų.	!	!			
Turn-on-delay time	t <sub>d(on)</sub>		4.9		ns	V <sub>DD</sub> = 15V, I <sub>D</sub> = 3.5A	
Rise time	t <sub>r</sub>		5.0		ns	$R_{G} \approx 6.0 \Omega$ , $V_{GS} = 10 V$	
Turn-off delay time	t <sub>d(off)</sub>		25.3		ns		
Fall time	t <sub>f</sub>		4.6		ns		
Total gate charge	$Q_g$		12.4		nC	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 5V I <sub>D</sub> = 3.5A	
Total gate charge	Qg		24.2		nC	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 5V	
Gate-source charge	O <sub>gs</sub>		5.2		nC	I <sub>D</sub> = 3.5A	
Gate drain charge	$Q_{gd}$		3.5		nC		
Source-drain diode		'					
Diode forward voltage <sup>(*)</sup>	$V_{SD}$		0.85	0.95	V	T <sub>j</sub> =25°C, I <sub>S</sub> = 6.6A, V <sub>GS</sub> =0V	
Reverse recovery time <sup>(‡)</sup>	t <sub>rr</sub>		26.3		ns	T <sub>j</sub> =25°C, I <sub>S</sub> = 3.5A,	
Reverse recovery charge <sup>(‡)</sup>	Q <sub>rr</sub>		26.6		nC	di/dt=100A/μs	

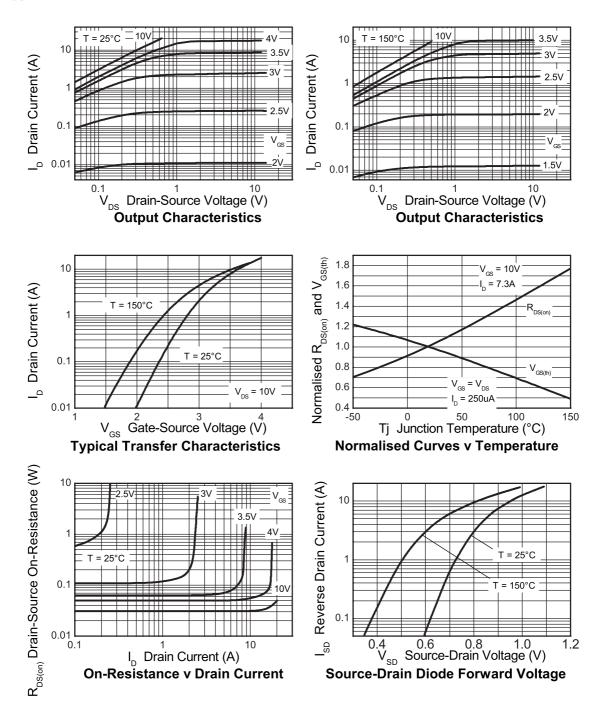
### NOTES:

<sup>(\*)</sup> Measured under pulsed conditions. Pulse width  $\leq$ 300 s; duty cycle  $\leq$ 2%.

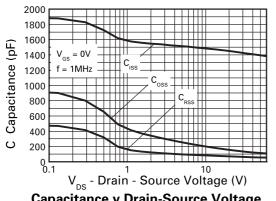
<sup>(†)</sup> Switching characteristics are independent of operating junction temperature.

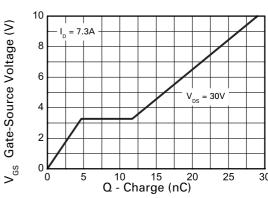
<sup>(‡)</sup> For design aid only, not subject to production testing.

# **Typical characteristics**



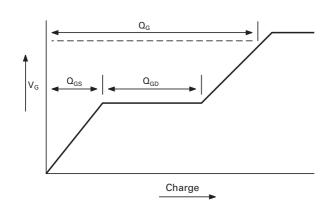
# **Typical characteristics**

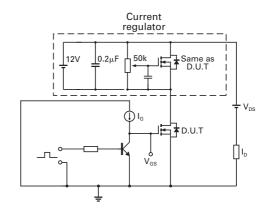




**Capacitance v Drain-Source Voltage** 

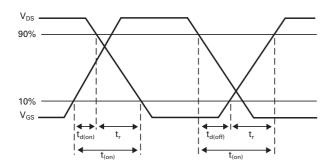
Gate-Source Voltage v Gate Charge

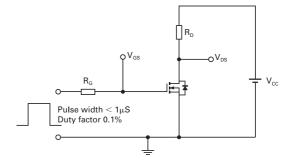




Basic gate charge waveform

Gate charge test circuit

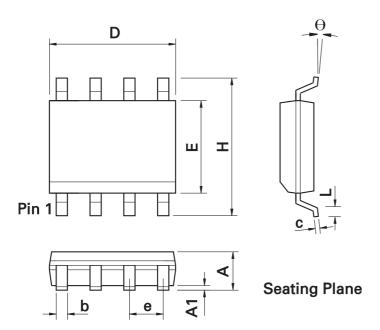




Switching time waveforms

Switching time test circuit

# Package outline - SO8



DIM	Inc	hes	Millin	neters	DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
Α	0.053	0.069	1.35	1.75	е	0.050 BSC		1.27 BSC	
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	С	0.008	0.010	0.19	0.25
Н	0.228	0.244	5.80	6.20	θ	0°	8°	0°	8°
Е	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

Note: Controlling dimensions are in inches. Approximate dimensions are provided in millimeters

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